FDP6690S/FDB6690S 30V N-Channel PowerTrench^o SyncFET[™] **General Description Features** This MOSFET is designed to replace a single MOSFET • 21 A, 30 V. $R_{\text{DS(ON)}} = 15.5 \text{ m}\Omega @ \text{V}_{\text{GS}} = 10 \text{ V}$ and parallel Schottky diode in synchronous DC:DC $R_{DS(ON)} = 23.0 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low · Includes SyncFET Schottky body diode $R_{\text{DS}(\text{ON})}$ and low gate charge. The FDP6690S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDP6690S/FDB6690S as the low-side switch in a • Low gate charge (11nC typical) synchronous rectifier is indistinguishable from the High performance trench technology for extremely performance of the FDP6035AL/FDB6035AL in parallel low R_{DS(ON)} and fast switching with a Schottky diode. · High power and current handling capability D D G **TO-263AB TO-220** D S **FDP Series** FDB Series Absolute Maximum Ratings TA=25°C unless otherwise noted Symbol Parameter Ratings Units V_{DSS} Drain-Source Voltage 30 v V_{GSS} Gate-Source Voltage ±20 V Drain Current Continuous I_{D} (Note 1) А 42 - Pulsed (Note 1) 140 P_D Total Power Dissipation @ $T_c = 25^{\circ}C$ W 48 Derate above 25°C W/°C 0.5 °C T_J, T_{STG} Operating and Storage Junction Temperature Range -55 to +150 ΤL Maximum lead temperature for soldering purposes, °C

	Therma	I Characteristics				
_	$R_{ ext{ ext{ ext{ ext{ ext{ ext{ ext{ ext$	Thermal Resistance, Junction-to-Case	2.6	°C/W		
_	$R_{ ext{ hetaJA}}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W		

Package Marking and Ordering Information

1/8" from case for 5 seconds

Device Marking	Device	Reel Size	Tape width	Quantity
FDB6690S	FDB6690S	13"	24mm	800 units
FDP6690S	FDP6690S	Tube	n/a	45

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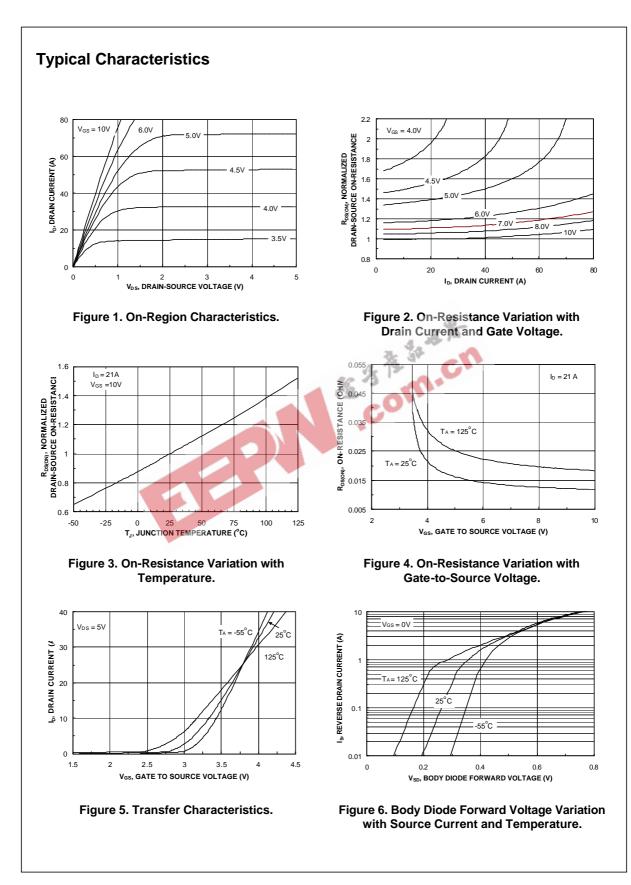
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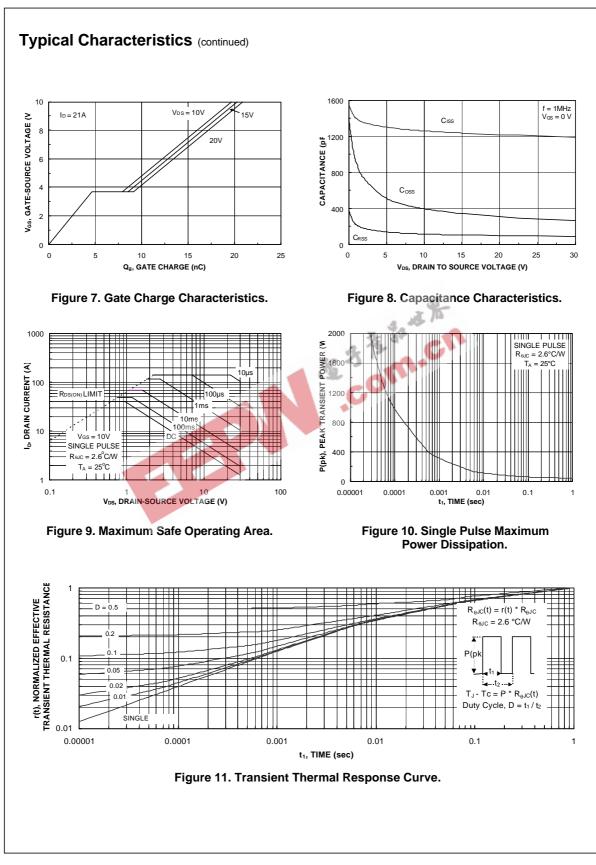
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	burce Avalanche Ratings (Note	2)				
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 25 \text{ V}$, $I_D = 11 \text{ A}$			140	mJ
I _{AR}	Drain-Source Avalanche Current				11	Α
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = 1mA$	30			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	I_D = 10mA, Referenced to 25°C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			500	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)	· ·	•		•	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 1mA$	1	2.2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 10mA, Referenced to 25°C	2	-4		mV/°0
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 V, I_D = 21 A$ $V_{GS} = 4.5 V, I_D = 17 A$ $V_{GS}=10 V, I_D = 21 A, T_J=125^{\circ}C$	n	12.0 18.5 18.0	15.5 23.0 22.5	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$	60			Α
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 23 \text{ A}$		33		S
Dynamic	c Characteristics					
Ciss	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		1238		pF
Coss	Output Capacitance	f = 1.0 MHz		342		pF
C _{rss}	Reverse Transfer Capacitance			104		pF
Switchir	g Characteristics (Note 2)		•		•	
t _{d(on)}	Turn–On Delay Time	$V_{DS} = 15 V$, $I_{D} = 1 A$,		11	20	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		9	18	ns
t _{d(off)}	Turn-Off Delay Time			23	37	ns
t _f	Turn-Off Fall Time			13	23	ns
Q _g	Total Gate Charge	$V_{DS} = 15 V, I_{D} = 21A,$		11	15	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		5		nC
Q _{gd}	Gate-Drain Charge			4		nC
Drain-S	ource Diode Characteristics					
V _{SD}	Drain–Source Diode Forward Voltage	$ \begin{array}{c} V_{GS} = 0 \ V, I_S = 3.5 \ A (\text{Note 1}) \\ V_{GS} = 0 \ V, I_S = 7 \ A (\text{Note 1}) \end{array} $		0.51 0.69	0.7	V
t _{rr}	Diode Reverse Recovery Time	I _F = 3.5 A,		21		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A}/\mu \text{s}$ (Note 2)		25		nC

Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
See "SyncFET Schottky body diode characteristics" below.

FDP6690S/FDB6690S



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FDP6690S/FDB6690S

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 FDP6690S.

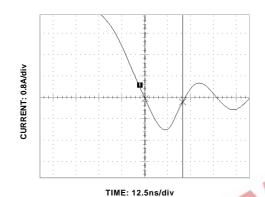


Figure 12. FDP6690S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDP6035AL).

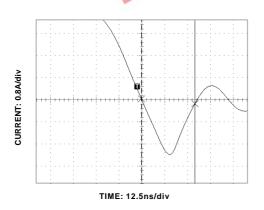


Figure 13. Non-SyncFET (FDP6035AL) body diode reverse recovery characteristic. Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

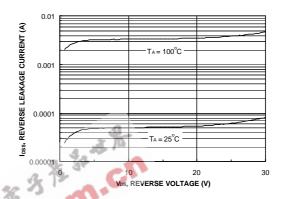


Figure 14. SyncFET diode reverse leakage versus drain-source voltage and temperature.

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